Abstracts

Microstrip Noncontacting Thickness Monitor

R.B. Hurley, I. Kaufman and R.P. Roy. "Microstrip Noncontacting Thickness Monitor." 1989 MTT-S International Microwave Symposium Digest 89.3 (1989 Vol. III [MWSYM]): 905-908.

A microwave technique for measurement of the height of a material on a metallic surface using a planar microstrip transmission line structure is presented. A device was designed to monitor the height of a film of water up to about 1 mm. The method produced consistant results and may be adapted for use without microwave frequency measurement devices.

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